



500.40120X00

**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

Applicant(s): T. OTSUBO, et al  
Serial No.: 09/855,674  
Filed: May 16, 2001  
For: APPARATUS FOR MONITORING THICKNESS OF  
DEPOSITED LAYER IN REACTOR AND DRY PROCESSING  
METHOD  
Group: 2877  
Examiner: K. Brown

**PROPOSED AMENDMENT TO THE DRAWINGS  
AND CORRECTED SUBSTITUTE DRAWINGS**

Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

September 22, 2003

Sir:

It is proposed that the drawings in the above-identified application be amended in accordance with the attached red-lined print and corrected drawings incorporating the changes are submitted herewith.

Respectfully submitted,

Melvin Kraus  
Registration No. 22,466  
ANTONELLI, TERRY, STOUT & KRAUS, LLP

MK/cee  
Attachment(s)  
(703) 312-6600

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